In the Claims:

Please amend the claims as follows:

1. (Currently amended) A charged particle beam device [(1)] to inspect or structure a specimen [(3)] comprising:

a) a charged particle beam source [(5)] to generate a charged particle beam [(7)];

b) a beam optical system [(16)] to direct the charged particle beam [(7)] onto said specimen [(3)]; and

c) a gas supply system [(10)] providing a gas [(12)] for the charged particle beam device [(1)];

the gas supply system [(10)] comprising a plurality of at least ten tubes [(14; 15; 22)] to direct said gas [(12)] towards a desired region [(68)] for interaction with the specimen [(3)].

2. (Currently amended) The charged particle beam device [(1)] according to claim 1, [whereby] wherein the length, L, of each tube [(14)] is larger than the square root of the inner cross section area, A, of the tube by more than 5 times, preferably by more than 50 times and even more preferred by more than 500 times.

3. (Currently amended) The charged particle beam device [(1)] according to claim 1, [or 2,] [whereby] wherein the gas supply system [(10)] comprises a plurality of more than 100, preferably more than 1000 and even more preferred more than 10,000 tubes [(14; 15; 22)] to direct said gas [(12)].

4. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1, [whereby] wherein the desired region [(68)] is the volume

taken by the charged particle beam [(7)] and/or the region where the charged particle beam [(7)] impinges onto the specimen [(3)].

5. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1, [whereby] wherein the charged particle beam device [(1)] provides a vacuum [(38)] with a pressure lower than $1x10^{-3}$ mbar and preferably lower than $1x10^{-4}$ mbar.

6. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1, [whereby] wherein the inner cross section area, A, of each tube [(14)] varies along the tube length, L, by less than a factor of 4, preferably by less than 20% and even more preferred by less than 10% compared to the cross section area, A, at the outlet [(32)] of the tube [(14)].

7. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1, [whereby] wherein the inner cross section area, A, at the outlet [(32)] of each tube [(14)] of the plurality of tubes [(15; 22)] is smaller than 50,000 μm^2, preferably smaller than 1000 μm^2 and even more preferred smaller than 10 μm^2.

8. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1, [whereby] wherein the inlets [(34)] of the tubes [(14)] are positioned within a dispensing pressure chamber [(13)] and preferably within a common dispensing pressure chamber [(13)].

9. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1, [whereby] wherein the at least ten tubes [(14)] are oriented essentially in parallel to each other.

10. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1 [whereby] wherein, the tubes [(14)] of the plurality of tubes [(15; 22)] are arranged as a bundle of tubes.

11. (Currently amended) The charged particle beam device [(1)] according to claim 10, [whereby] wherein the bundle of tubes form a tube plate [(22)] with the tubes [(14)] reaching from the front side [(24)] of the tube plate [(22)] to the reverse side [(26)] of the tube plate.

12. (Currently amended) The charged particle beam device [(1)] according to claim 11, [whereby] wherein the density of tube outlets [(32)] on the reverse side [(26)] of the tube plate is within the range of 10^2 1/cm^2 to 10^7 1/cm^2 and preferably within the range of 10^4 1/cm^2 to 10^6 1/cm^2.

13. (Currently amended) The charged particle beam device according to claim 1, [any of the previous claims] [whereby] wherein the inner cross section, A, of each tube [(14)] of the plurality of tubes [(15; 22)] is characterized by a characteristic diameter, D.

14. (Currently amended) The charged particle beam device according to claim 13, [whereby,] wherein during normal operation, the free path length [(30)] of the gas [(12)] at the outlet [(32)] of each tube [(14)] is larger than 1/10 of the length of the tube, L, preferably larger than one time the length of the tube, L, and even more preferred larger than ten times the length of the tube, L.

15. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1, [whereby,] wherein during normal operation, the peaking-ratio of the gas [(12)] at the outlet of each tube [(32)] of the plurality of tubes [(15; 22)] is

larger than two, preferably larger than five and even more preferred larger than 20.

16. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1, [whereby,] wherein during normal operation, the pressure at the inlet [(36)] of each tube [(14)] is smaller than 10 mbar, preferably smaller than 1 mbar and even more preferred smaller than 0[,].1 mbar.

17. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 1, [whereby] wherein the beam optical system [(16)] comprises a final focus lens [(18)] to focus the charged particle beam [(7)] onto the specimen [(3)].

18. (Currently amended) The charged particle beam device [(1)] according to claim 17, [whereby,] wherein during normal operation, the plurality of tubes [(15; 22)] directs the gas [(12)] into the charged particle beam [(7)] in the region between the final focus lens [(18)] and the surface of the specimen [(3)].

19. (Currently amended) The charged particle beam device [(1)] according to [any of the] claim[s] 17 [or 18], [whereby] wherein the tubes [(14)] of the plurality of tubes [(15; 22)] are arranged at an angle, α, smaller than 60 degrees, preferably smaller than 40 degrees, and even more preferred smaller than 20 degrees with respect to the optical axis [(52)] of the final focus lens to direct the gas [(12)] towards the specimen [(3)].

20. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 17, [whereby] wherein the beam optical system [(16)] comprises a reference electrode [(56)] to generate an electric field to accelerate the ionized gas [(12)] towards the specimen [(3)].

21. (Currently amended) The charged particle beam device [(1)] according to [any of the] claim[s] 11 [to 20], [whereby] wherein the plurality of tubes [(15)] comprises at least two tube plates [(22)] and preferably at least eight tube plates [(22)].

22. (Currently amended) The charged particle beam device [(1)] according to claim 21, [whereby] wherein the at least two tube plates [(22)] are arranged as a semicircle around the optical axis of the final focus lens [(52)].

23. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 21, [whereby] wherein the gas [(12)] is a neutral gas when passing through the tubes [(14)].

24. (Currently amended) The charged particle beam device [(1)] according to claim 23, [whereby] wherein the neutral gas [(12)] is a neutral gas like N_2 or an inert gas like He, Ne, Ar; Kr, Xe, or CH_4 or a mixture of the above mentioned gases.

25. (Currently amended) The charged particle beam device [(1)] according to [any of the previous claims,] claim 21, [whereby] wherein the at least ten tubes [(14; 15; 22)] are positioned in the vicinity of the specimen [(3)].